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01 PE JC139
JUL 09 2004
PATENT & TRADEMARK OFFICE

~~5/~~re Application of:

Examiner: J. Kang

Group Art Unit: 2874

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July 8, 2004

THIRD INFORMATION DISCLOSURE STATEMENT

This is not a response on the merits to the Office Action mailed on April 8,

07/13/2004 WABDEL1 0000136 10730033
01 FC:1806 180.00 0P

01 FC:1806

The concise explanation of relevance for the non-English documents may be found, inter alia, in the English language abstracts and/or translations attached thereto.¹ Also, the concise explanation of relevance for JP 9-96746 may be found in U.S. Patent No. 5,835,646, which are both in the same patent family. The concise explanation of relevance for JP 10-294254 may be found in U.S. Patent No. 6,097,472, which are both in the same patent family. The concise explanation of relevance for JP 2001-284635 may be found in U.S. Patent No. 6,563,137 B2, which are both in the same patent family. The concise explanation of relevance for JP 2000-337872 may be found in U.S. Patent No. 6,505,409 B2, which are both in the same patent family. The concise explanation of relevance for JP 11-196069 may be found in U.S. Patent No. 6,366,375 B1, which are both in the same patent family. The concise explanation of relevance for JP 2000-31189 and JP 2000-31190 may be found in U.S. Patent No. 6,509,645 B2 and in U.S. Patent Application Publication Nos. 2002/0132462 A1; 2003/0020164 A1 and 2004/0061224 A2, which are all in the same patent family.

CONCLUSION

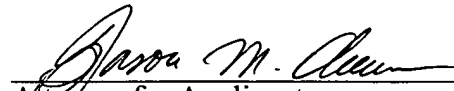
It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

We also enclose a check for the required fee of \$180.00 to cover the Information Disclosure Statement under 37 C.F.R. § 1.97(c)(2).

^{1/} Applicant notes that the translations of JP 9-270751 and JP 11-72750 were generated by a computer at the Japanese Patent Office web site and should be considered accordingly. Also, Applicant notes that JP 9-270751 is already of record and is submitted herewith solely to accompany its computer-generated translation.

Applicant's undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

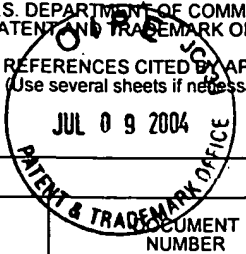
A handwritten signature in cursive script, appearing to read "Jason M. Okun", is written over a horizontal line.

Attorney for Applicant

Jason M. Okun

Registration No. 48,512

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.017455		APPLICATION NO. 10/730,033	
				APPLICANT Toshihiko Ouchi			
				FILING DATE December 9, 2003		GROUP 2874	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,835,646	11/10/98	Yoshimura et al.	385	14	
		6,097,472	08/01/00	Tanaka et al.	355	47	
		6,343,171 B1	01/29/02	Yoshimura et al.	385	50	
		6,516,104 B1	02/04/03	Furuyama et al.	385	14	
		5,712,504	01/27/98	Yano et al.	257	452	
		6,505,409 B2	01/14/03	Toda et al.	33	366.24	
		6,509,645 B2	01/21/03	Tatsumi et al.	257	738	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	9-270751	10/14/97	Japan			Translation
	JP	59-75656	04/28/84	Japan			Translation
	JP	8-220357	8/30/96	Japan			Abstract
	JP	9-96746	04/8/97	Japan			Abstract
	JP	10-294254	11/04/98	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		Steven C. Binari et al., "GaN FETs for Microwave and High-temperature Applications," 41(2) Solid-State Electronics 177-80 (1997).					
		Seikoh Yoshida et al., "High-temperature Reliability of GaN Metal Semiconductor Field-Effect Transistor and Bipolar Junction Transistor," 85(11) J. Appl. Phys. 7931-34 (June 1999).					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,563,137 B2	05/13/03	Uchida	257	84	
		6,499,899 B1	12/31/02	Shirakawa et al.	385	88	
		6,611,000 B2	08/26/03	Tamura et al.	257	80	03/12/02
		6,366,375 B1	04/02/02	Sakai et al.	359	115	
		5,191,219	03/02/93	Linke	250	551	
		2004/0061224 A2	04/01/04	Tatsumi et al.	257	737	09/27/02
		2003/0020164 A1	01/30/03	Tatsumi et al.	257	737	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	11-54406	02/26/99	Japan			Abstract
	JP	11-72750	03/16/99	Japan			Translation
	JP	11-111609	04/23/99	Japan			Abstract
	JP	11-196069	07/21/99	Japan			Abstract
	JP	2000-31189	01/28/00	Japan			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/0167013 A1	11/14/02	Iwasaki et al.	257	79	
		2002/0132462 A1	09/19/02	Tatsumi et al.	438	613	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	2000-31190	01/28/00	Japan			Abstract
	JP	2000-235127	08/29/00	Japan			Abstract
	JP	2000-337872	12/08/00	Japan			Abstract
	JP	2001-284635	10/12/01	Japan			Abstract
	JP	61-28240	02/07/86	Japan			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

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